

**Search Notes**

Application/Control No.

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Examiner

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Applicant(s)/Patent under  
Reexamination

MA ET AL.

Art Unit

2638

**SEARCHED**

Class	Subclass	Date	Examiner
375	229-236 & Iterative	6/30/2005	JP
	316	6/30/2005	JP
	346	6/30/2005	JP
	348	6/30/2005	JP

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East USPAT/USPGPUB EPO/JPO	6/30/2005	JP
Inventor Name Search	6/30/2005	JP
IEEE iterative AND channel AND estimate	6/30/2005	JP

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